


<b>Search Notes</b> 	<b>Application/Control No.</b> 10658630	<b>Applicant(s)/Patent Under Reexamination</b> LEE ET AL.
	<b>Examiner</b> Goetze, Simon A	<b>Art Unit</b> 2617

SEARCHED			
Class	Subclass	Date	Examiner
370	328	2/2/2007	SAG
370	338	2/2/2007	SAG
370	465	2/2/2007	SAG
370	466	2/2/2007	SAG
398	58	2/2/2007	SAG
398	59	2/2/2007	SAG
398	60	2/2/2007	SAG
398	61	2/2/2007	SAG
398	62	2/2/2007	SAG
398	63	2/2/2007	SAG
398	64	2/2/2007	SAG

SEARCH NOTES		
Search Notes	Date	Examiner
EAST image and keyword search (USPAT; US-PGPUB; USOCR; JPO; EPO; DERWENT; IBM_TDB).	2/2/2007	SAG
Consulted with Edan Orgad (Class 455), Chau T. Nguyen and Melvin Marcelo (both of 370).	2/2/2007	SAG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner